Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/603,318	CHUAH ET AL.	
Examiner	Art Unit	_
David L. Vanik	1615	

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Class	Subclass	Date	Examiner
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East-See Attached	5/15/2006	DV
Inventor Search	5/15/2006	DV
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